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GUJARAT TECHNOLOGICAL UNIVERSITY PDDC - SEMESTER- VI • EXAMINATION - SUMMER-2017

Subject Code: X61102 Date: 02/05/2017 Subject Name: VLSI Technology and Design Time: 10.30AM to 01:00PM **Total Marks: 70 Instructions:** 1. Attempt all questions. 2. Make suitable assumptions wherever necessary. 3. Figures to the right indicate full marks. (a) Draw and explain Y chart fort VLSI Design flow. Also draw simplified VLSI **Q.1** 07 design flow at different abstraction levels. (b) List and explain importance of different CAD tolls used for VLSI design. 07 **Q.2** Explain n-well CMOS fabrication with necessary diagrams. 07 (a) (b) Define design rules for layout design in VLSI Technology. List and explain 07 types of design rules. Draw layout of CMOS inverter with necessary information. OR **(b)** Explain latch-up and its prevention in CMOS technology. 07 (a) Derive drain current equation in linear region and saturation region for NMOS. 07 0.3 **(b)** Define scaling in VLSI Technology. 07 OR Explain on chip clock generation and distribution. 07 0.3 (a) **(b)** Explain difference between FPGA and CPLD. **07** A CMOS inverter has $V_{TO,n} = 0.8 \text{ V}$, $V_{TO,p} = -0.8 \text{ V}$, and $k_n = k_p$. Obtain V_{IL} 07 0.4 V_{IH} , V_{OH} , V_{OL} , NM_H and NM_L for $V_{DD} = 5v$. A CMOS inverter has $\mu_n c_{ox} = 120 \ \mu A/V^2 \ \mu_p c_{ox} = 60 \ \mu A/V^2$, $V_{TO,n} = 0.8 \ V$, **07** $V_{TO,p} = -1.0 \text{ V}, T_{PHL} = 0.2 \text{ ns}, T_{PLH} = 0.15 \text{ ns}, V_{DD} = 3 \text{ V} C_{load} = 300 \text{ ff}$ Determine (W/L)n and (W/L)p Draw CMOS implementation for following Boolean equation 0.4 07 Z = A(D + E) + BCAssume that (W/L)n = 10 for all NMOS and (W/L)p = 15 for all PMOS. Find (W/L) equation for NMOS and PMOS. (b) Draw and explain SR flip flop using CMOS Technology. 07 07 **Q.5** (a) Write short notes on built in self test techniques. **(b)** Explain Basic Principles of pass transistor circuits. 07 Q.5 Explain CMOS Dynamic Circuit Techniques. 07 **(b)** Write short notes on Adhoc Testable design techniques. 07
